

Europe Information & Control, Metrics, and Physical Interfaces & Carriers TC Chapters Joint Meeting Summary and Minutes

SEMICON Europa
October 9, 2013
Dresden, Germany

Next Committee Meeting

SEMICON Europa 2014
Grenoble, France

Table 1 Meeting Attendees

Co-Chairs: Alfred Honold (InReCon), Frank Petzold (Trustsec)

SEMI Staff: James Amano

<i>Company</i>	<i>Last</i>	<i>First</i>	<i>Company</i>	<i>Last</i>	<i>First</i>
Global Foundries	Rothe	Jan	Fraunhofer	Pfützner	Lothar
Tokyo Electron	Mashiro	Supika			
Solvay Chemicals	Collard	Jean-Marie			
Fraunhofer	Schellenberger	Martin			
Consultant	Georgi	Ralf			

Table 2 Leadership Changes

None

Table 3 Ballot Results

Passed ballots and line items will be submitted to the ISC Audit & Review Subcommittee for procedural review.

Failed ballots and line items were returned to the originating task forces for re-work and re-balloting.

None

Table 4 Authorized Ballots

None

Table 5 Authorized Activities

None

Note: SNARFs and TFOFs are available for review on the SEMI Web site at:

<http://downloads.semi.org/web/wstdsbal.nsf/TFOFSNARF>

Table 6 New Action Items

<i>Item #</i>	<i>Assigned to</i>	<i>Details</i>
EUEAC-201410-1	Alfred Honold	Draft TFOF and SNARF for E48 revision.

Table 7 Previous Meeting Action Items

None

1 Welcome, Reminders, and Introductions

Co-chair Alfred Honold called the meeting to order at 11:30. The meeting reminders on antitrust issues, intellectual property issues and holding meetings with international attendance were reviewed. Attendees introduced themselves.

Attachment: Required Elements June 2, 2010.ppt

2 Staff Report

2.1 SEMI Staff Report

James Amano reported. Of note:

- An additional ballot cycle has been added to accommodate meetings held in January and February.
 - Cycle 8, 2013
 - Ballot Submission Date: Nov 15, 2013
 - Voting Period Starts: Nov 29, 2013
 - Voting Period Ends: Dec 31, 2013

Attachment: SEMI Staff Report (Europa 2013) rev2.ppt

3 Liaison Reports

3.1 Information & Control Committee

3.1.1 Japan Chapter Highlights

- Two new TFs have been formed:
 - Japan I&CC Maintenance TF
 - Leaders: Mitsuhiro Matsuda (Hitachi Kokusai Electric), Hideaki Ogihara (Algo System)
 - Fiducial Mark Interoperability TF
 - Leader: Mitsuhiro Matsuda (Hitachi Kokusai Electric)
- The AMHS TF has been disbanded.

Attachment: JA_ICC_SEMICON-EU_2013_R0.5

3.1.2 Korea Chapter Highlights

- GEM300 TF
 - 4946B (E87 and E87.1 Revision) is in cycle 6. It will be reviewed at Nov 8, 2013 meeting

- 5320C (E116 and E116.1 Revision) is waiting for GCS voting result for cycle 7.

Attachment: KR_I&C_liaison_20131001.ppt

3.1.3 NA Chapter Highlights

- Process Control Systems (PCS) TF – new SNARF
 - [5650] Line Item Revisions to SEMI E133, Specification for Automated Process Control Systems Interface and SEMI E133.1, Provisional Specification for XML Messaging for Process Control Systems (PCS)
- GEM300 TF – new SNARF
 - [5618] New Standard: Specification for Preservation of Recipe Integrity
- Standards to receive inactive status
 - SEMI E54.15 Sensor/Actuator Network Communication Specification for SafetyBUS p
 - SEMI E147 Guide for Equipment Data Acquisition (EDA)

Attachment: NA I&C report October 2013.ppt

3.2 Metrics Committee

3.2.1 North America Chapter

- Wait Time Waste TF – new SNARFs
 - New Subordinate Standard, Specification for Product Time Measurement Active in GEM 300 Production Equipment
- Equipment RAMP Metrics TF – new SNARFs
 - Revision to SEMI E10, Specification for Definition and Measurement of Equipment Reliability, Availability, and Maintainability (RAM) and Utilization
 - Revision to SEMI E79-1106, Specification for Definition and Measurement of Equipment Productivity and for Reconciliation with SEMI E10-0312

Attachment: NA Metrics Report Oct 2013 MT

3.2.2 Japan Chapter

Supika Mashiro commented that most Metrics activity is in NA, but that Japan members are contributing to the Cycle Time Measurement and Waste Time Wait efforts.

3.3 Physical Interfaces and Carriers Committee

3.3.1 North America

- 450 mm IPIC TF – New SNARFs
 - Line Item Revisions to SEMI E158-1110, Mechanical Specification for Fab Wafer Carrier Used to Transport and Store 450 mm Wafers (450 FOUP) and Kinematic Coupling
 - Line Item Revisions to SEMI E159-0912, Mechanical Specification for Multi Application Carrier (MAC) Used to Transport and Ship 450 mm Wafers
- IPPI TF – New SNARF
 - Line Item Revision to SEMI E166-0513, Specification for 450 mm Cluster Module Interface: Mechanical Interface and Transport Standard

Attachment: NA PIC Report Oct 2013 MT

3.3.2 Japan

- New Fiducial Mark Interoperability Task Force
- 450 AMHS TF

- New SNARF for Doc. 5424, Revisions to SEMI E156-0710, Mechanical Specification for 450 mm AMHS Stocker to Transport Interface, with title change to Mechanical Interface Specification for 450 mm AMHS Stocker to Transport Equipment

Attachment: JP_PIC_EU EA_R0.2

4 Ballot Review

None

5 Subcommittee & Task Force Reports

5.1 Process Control Systems Task Force (I&C)

Martin Schellenberger reported. The group serves as a counterpart to NA PCS-TF, which works to define an online Process Control System (PCS) Architecture Framework inclusive of run to run, fault detection and classification, and statistical process control capabilities. Goals:

- Bring the requirements of European companies into the standardization process
- Review the recommended approach
- Keep people informed, collect and provide feedback
- Potential future topics: PdM standardization, RoI standardization

Attachment: 2013-10 PCS-TF-Report for European EAC.ppt

5.2 International Reticle SMIF Pod and Load Port Interoperability Task Force (PIC)

Jan Rothe reported.

- Task Force completed the ballot of a Related Information to SEMI E19; E19.3, E111 and E112 with list of known sensor positions and advice for sensor implementation
- Ballots passed technical review in July 2013
- Task Force decided to prepare a survey about RSP/LP purge port locations for Reticle SMIF Pods
 - TF plans to obtain overview of how many locations there are
 - First overview available and ready for discussion
 - Discussion whether or not to include this type of information in a related information document will be held at a later time (after completion of survey)

Attachment: Reticle Pod LP Interoperability TF Report 2013-10.ppt

6 Five-year Review

- SEMI E48-1101 (Reapproved 1107) - Specification for SMIF Indexer Volume Requirement
 - Co-chair Alfred Honold described that he was in the process of recruiting members to revise E48, and that the effort should be considered ongoing. The standard is currently written only for wafers, but reticles will be added in the revision. **AI:** Alfred Honold to draft TFOF and SNARF for E48 revision activity.

Motion: To consider the E48 revision effort “ongoing”

By / 2nd: Frank Petzold/Jan Rother

Discussion: None

Vote: 6-0

- SEMI E54.14-0309 Specification for Sensor/Actuator Network Communications for PROFINET
- SEMI E54.8-0309 Specification for Sensor/Actuator for Network Communications for PROFIBUS-DP

- Co-chair Alfred Honold stated that E54.14 and E54.8 were driven by Siemens, which is no longer active in semiconductors. The two standards will receive inactive status in 2014.

7 Old Business

None

8 New Business

None

9 Action Item Review

9.1 Open Action Items

James Amano reviewed the open action items. These can be found in the Open Action Items table at the beginning of these minutes.

9.2 New Action Items

James Amano reviewed the new action items. These can be found in the New Action Items table at the beginning of these minutes.

10 Next Meeting and Adjournment

The next meeting of the EU Chapters of the I&C, Metrics, and PIC Committees will be held during SEMICON Europa 2014 in Grenoble, France.

Minutes submitted by:

James Amano

SEMI HQ

Table 8 Index of Available Attachments #1

#	Title	#	Title
	Required Elements June 2, 2010.ppt		NA PIC Report Oct 2013 MT
	SEMI Staff Report (Europa 2013) rev2.ppt		JP_PIC_EU EA_R0.2
	JA_ICC_SEMICON-EU_2013_R0.5		2013-10 PCS-TF-Report for European EAC.ppt
	KR_I&C_liaison_20131001.ppt		Reticle Pod LP Interoperability TF Report 2013-10.ppt
	NA I&C report October 2013.ppt		
	NA Metrics Report Oct 2013 MT		

#1 Due to file size and delivery issues, attachments must be downloaded separately. A .zip file containing all attachments for these minutes is available at www.semi.org.